

<b>Notice of References Cited</b>	Application/Control No. 10/815,976	Applicant(s)/Patent Under Reexamination FUKUI ET AL.	
	Examiner Thanh-Truc Trinh	Art Unit 1753	Page 1 of 1

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*	B	US-2002/0040728 A1	04-2002	Yoshikawa, Masaru	136/263
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**NON-PATENT DOCUMENTS**

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*	U	Website Solaronix <a href="http://www.solaronix.ch/ruthenium/pdf/ruthenium620-1H3TBA_data_sheet.htm">http://www.solaronix.ch/ruthenium/pdf/ruthenium620-1H3TBA_data_sheet.htm</a> from 01/02/2000, 3 pages.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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